Se	earch	Note	S

Application/Control No.	Applicant(s)/Patent under Reexamination	
08/427,866	SUGIYAMA ET AL.	
Examiner	Art Unit	
Hai C. Pham	2861	

	SEAR	CHED	
Class	Subclass	Date	Examiner
369	94, 44.23, 100, 275.1- 275.4	11/6/2006	HP
	286, 288		

INT	TERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	l		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Text Search	11/6/2006	НР